*nanomaterials*

MDPI

*Correction*

# Correction: Klauser et al. Line Tension and Drop Size Dependence of Contact Angle at the Nanoscale. *Nanomaterials* 2022, *12*, 369

**Waldemar Klauser *, Fabian T. von Kleist-Retzow and Sergej Fatikow**

Division Microrobotics and Control Engineering, Department of Computing Science, University of Oldenburg, D-26129 Oldenburg, Germany

* Correspondence: waldemar.klauser@uni-oldenburg.de

## 1. Text Correction

There was an unclear passage in the original publication [1]. The value of the line tension is actually negative. This is clearly seen in Figure 3b. While it is implicit, we would like to point out that the value of the line tension we give is an absolute value, and we would like to add a minus to the value range extracted from Figure 3b.

A correction has been made to "*Section 3*, *Results*":

"From this fit, we determined an absolute value for the apparent line tension, $\tau = 4.02 \times 10^{-7}$ J/m. Furthermore, for better display of the validity of the measurement results, $\theta_C$ versus one divided by the radius of the spheres was plotted too (see Figure 3b). The solid red line corresponds to the previously determined $\tau$. The two additional dotted lines correspond to 2 $\tau$ and 1/2 $\tau$. Thus, more than 90% of the data points are located in the funnel that spans between $-8.04 \times 10^{-7}$ J/m $< \tau < -2.01 \times 10^{-7}$ J/m."

## 2. Reference Correction

In the original publication, Ref. [22] was not cited correctly, it should change as follows:

New Ref. 22: Zhao, B.; Luo, S.; Bonaccurso, E.; Auernhammer, G.K.; Deng, X.; Li, Z.; Chen, L. Resolving the Apparent Line Tension of Sessile Droplets and Understanding its Sign Change at a Critical Wetting Angle. *Phys. Rev. Lett.* **2019**, *123*, 94501

The authors apologize for any inconvenience caused and state that the scientific conclusions are unaffected. This correction was approved by the Academic Editor. The original publication has also been updated.

## Reference

1. Klauser, W.; von Kleist-Retzow, F.T.; Fatikow, S. Line Tension and Drop Size Dependence of Contact Angle at the Nanoscale. *Nanomaterials* **2022**, *12*, 369. [CrossRef] [PubMed]

**Disclaimer/Publisher's Note:** The statements, opinions and data contained in all publications are solely those of the individual author(s) and contributor(s) and not of MDPI and/or the editor(s). MDPI and/or the editor(s) disclaim responsibility for any injury to people or property resulting from any ideas, methods, instructions or products referred to in the content.

check for updates

**Citation:** Klauser, W.; von Kleist-Retzow, F.T.; Fatikow, S. Correction: Klauser et al. Line Tension and Drop Size Dependence of Contact Angle at the Nanoscale. *Nanomaterials* 2022, *12*, 369. *Nanomaterials* **2023**, *13*, 2847. https://doi.org/10.3390/nano13212847

Received: 16 June 2023
Revised: 18 July 2023
Accepted: 8 September 2023
Published: 27 October 2023

**Copyright:** © 2023 by the authors. Licensee MDPI, Basel, Switzerland. This article is an open access article distributed under the terms and conditions of the Creative Commons Attribution (CC BY) license (https://creativecommons.org/licenses/by/4.0/).